Notice of References Cited

Application/Control No. 10/532,864	Applicant(s)/Par Reexamination KANO ET AL.			
Examiner	Art Unit			
Hau V. Phan	3618	Page 1 of 1		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,174,978	02-2007	Taniguchi et al.	180/65.1
*	В	US-4,884,650	12-1989	Fujiki et al.	180/197
*	С	US-4,938,306	07-1990	Sumiyoshi et al.	180/233
*	D	US-5,353,889	10-1994	Hamada, Tetsurou	180/242
*	Е	US-5,513,719	05-1996	Moroto et al.	180/65.4
*	F	US-5,988,307	11-1999	Yamada et al.	180/243
*	G	US-6,002,979	12-1999	Ishizu, Takeshi	701/86
*	Н	US-6,041,877	03-2000	Yamada et al.	180/65.2
*	1	US-6,067,801	05-2000	Harada et al.	60/705
*	J	US-6,155,364	12-2000	Nagano et al.	180/65.2
*	K	US-6,258,006	07-2001	Hanyu et al.	477/5
*	L	US-6,321,865	11-2001	Kuribayashi et al.	180/243
*	М	US-6,378,638	04-2002	Mizon et al.	180/65.6

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	×						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.